

INSPECTION METHOD FOR ARRAY SUBSTRATE  
AND INSPECTION DEVICE FOR THE SAME

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ABSTRACT OF THE DISCLOSURE

Disclosed are an inspection method for a disconnection of a storage capacitor line and an inspection device for the same in an inspection of an array substrate used in a liquid crystal display apparatus. An inspection method for an array substrate is constituted, in which a quantity of charges stored in the storage capacitor becomes C (Vd<sub>1</sub>-Vcs<sub>1</sub>) by supplying simultaneously a pulse signal Vd and a pulse signal Vcs to the storage capacitor from a signal line and a Cs line on a TFT array substrate, and an influence of the disconnection of the Cs line is taken into consideration when the above-described quantity of charges is detected in a reading circuit. Note that the above-described inspection is performed not for all the storage capacitors, but for one storage capacitor in each Cs line. Thus, the inspection for all the Cs lines in liquid crystal panels from 14 inch diagonal to 18 inch diagonal is terminated in about 1 to 2 seconds.

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